SCLS310A - JANUARY 1996 - REVISED MAY 1997

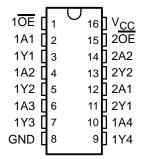
- High-Current 3-State Outputs Drive Bus Lines, Buffer Memory Address Registers, or Drive up to 15 LSTTL Loads
- Inverting Outputs
- Package Options Include Plastic Small-Outline (D) and Ceramic Flat (W)
   Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J)
   300-mil DIPs

#### description

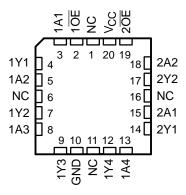
These hex buffers and line drivers are designed specifically to improve both the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters. The 'HC368 are organized as dual 4-line and 2-line buffers/drivers with active-low output-enable (1OE and 2OE) inputs. When OE is low, the device passes inverted data from the A inputs to the Y outputs. When OE is high, the outputs are in the high-impedance state.

The SN54HC368 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74HC368 is characterized for operation from –40°C to 85°C.

#### SN54HC368 . . . J OR W PACKAGE SN74HC368 . . . D OR N PACKAGE (TOP VIEW)



# SN54HC368 . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

# FUNCTION TABLE (each buffer/driver)

INP	JTS	OUTPUT
OE	Α	Y
Н	Х	Z
L	Н	L
L	L	Н



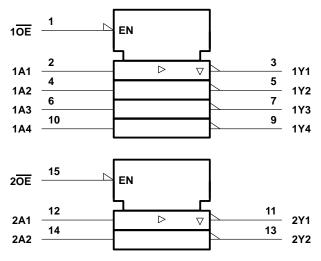
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### SN54HC368, SN74HC368 **HEX BUFFERS AND LINE DRIVERS** WITH 3-STATE OUTPUTS

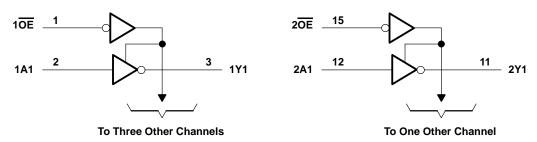
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#### logic symbol<sup>†</sup>



<sup>&</sup>lt;sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the D, J, N, and W packages.

#### logic diagram (positive logic)



Pin numbers shown are for the D, J, N, and W packages.

## absolute maximum ratings over operating free-air temperature range‡

Supply voltage range, V <sub>CC</sub>	0.5 V to 7 V
Input clamp current, $I_{IK}$ ( $V_I < 0$ or $V_I > V_{CC}$ ) (see Note 1)	±20 mA
Output clamp current, I <sub>OK</sub> (V <sub>O</sub> < 0 or V <sub>O</sub> > V <sub>CC</sub> ) (see Note 1)	±20 mA
Continuous output current, $I_O$ ( $V_O = 0$ to $V_{CC}$ )	±35 mA
Continuous current through V <sub>CC</sub> or GND	±70 mA
Package thermal impedance, θ <sub>JA</sub> (see Note 2): D package	113°C/W
N package	78°C/W
Storage temperature range, T <sub>stq</sub>	-65°C to 150°C

<sup>‡</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.



NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

<sup>2.</sup> The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.

### recommended operating conditions

			SI	SN54HC368		SN	174HC36	8	UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vсс	Supply voltage		2	5	6	2	5	6	V
		V <sub>CC</sub> = 2 V	1.5			1.5			
VIH	High-level input voltage	V <sub>CC</sub> = 4.5 V	3.15			3.15			V
		VCC = 6 V	4.2			4.2			
	Low-level input voltage	V <sub>CC</sub> = 2 V	0		0.5	0		0.5	V
VIL		V <sub>CC</sub> = 4.5 V	0		1.35	0		1.35	
		V <sub>CC</sub> = 6 V	0		1.8	0		1.8	
٧ <sub>I</sub>	Input voltage		0		VCC	0		VCC	V
٧o	Output voltage		0		VCC	0		VCC	V
		V <sub>CC</sub> = 2 V	0		1000	0		1000	
t <sub>t</sub>	Input transition (rise and fall) time	$V_{CC} = 4.5 \text{ V}$	0		500	0		500	ns
		V <sub>CC</sub> = 6 V	0		400	0		400	
TA	Operating free-air temperature		-55	_	125	-40		85	°C

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETER	TEST CONDITIONS		V	Т	A = 25°C	;	SN54HC368		SN74HC368		
PARAMETER			vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
			2 V	1.9	1.998		1.9		1.9		
		I <sub>OH</sub> = -20 μA	4.5 V	4.4	4.499		4.4		4.4		
Voн	VI = VIH or VIL		6 V	5.9	5.999		5.9		5.9		V
		$I_{OH} = -6 \text{ mA}$	4.5 V	3.98	4.3		3.7		3.84		
		$I_{OH} = -7.8 \text{ mA}$	6 V	5.48	5.8		5.2		5.34		
	VI = VIH or VIL	I <sub>OL</sub> = 20 μA	2 V		0.002	0.1		0.1		0.1	
			4.5 V		0.001	0.1		0.1		0.1	
VOL			6 V		0.001	0.1		0.1		0.1	V
		$I_{OL} = 6 \text{ mA}$	4.5 V		0.17	0.26		0.4		0.33	
		$I_{OL} = 7.8 \text{ mA}$	6 V		0.15	0.26		0.4		0.33	
lį	$V_I = V_{CC}$ or 0		6 V		±0.1	±100		±1000		±1000	nA
loz	$V_O = V_{CC}$ or 0		6 V		±0.01	±0.5		±10		±5	μΑ
Icc	$V_I = V_{CC}$ or 0,	I <sub>O</sub> = 0	6 V			8		160		80	μΑ
C <sub>i</sub>			2 V to 6 V		3	10		10		10	рF

### SN54HC368, SN74HC368 **HEX BUFFERS AND LINE DRIVERS** WITH 3-STATE OUTPUTS

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# switching characteristics over recommended operating free-air temperature range, $C_L$ = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	Vaa	TA	√ = 25°C	;	SN54H	C368	SN74HC368		UNIT	
PARAMETER	(INPUT)	(OUTPUT)	VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT	
			2 V		50	95		145		120		
<sup>t</sup> pd	Α	Υ	4.5 V		12	19		29		24	ns	
•			6 V		10	16		25		20		
_		Y	2 V		100	190		285		238		
t <sub>en</sub>	ŌĒ		4.5 V		26	38		57		48	ns	
				6 V		21	32		48		41	
	ŌĒ	Y	2 V		50	175		265		240		
<sup>t</sup> dis			Υ	4.5 V		21	35		53		48	ns
			6 V		19	30		45		41		
t <sub>t</sub>		Any	2 V		28	60		90		75		
			Any	Any	4.5 V		8	12		18		15
				6 V		6	10		15		13	

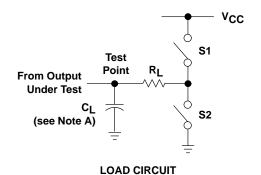
# switching characteristics over recommended operating free-air temperature range, $C_L$ = 150 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	Vaa	T <sub>A</sub> = 25°C		SN54HC368		SN74HC368		UNIT											
FARAMETER	(INPUT)	(OUTPUT)	VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT										
<sup>t</sup> pd			2 V		70	120		180		150											
	Α	Y	Y	4.5 V		17	24		36		30	ns									
																6 V		14	20		31
	ŌĒ	Y		2 V		140	230		345		285										
t <sub>en</sub>			4.5 V		30	46		69		57	ns										
				<u> </u>		6 V		28	39		59		48								
			Any	2 V		45	210		315		265										
t <sub>t</sub>		Any		4.5 V		17	42		63		53	ns									
			6 V		13	36		53		45											

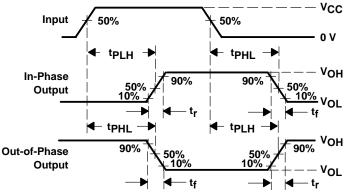
## operating characteristics, $T_A = 25^{\circ}C$

	PARAMETER	TEST CONDITIONS	TYP	UNIT
C <sub>pd</sub>	Power dissipation capacitance per buffer/driver	No load	35	pF

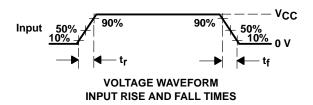
#### PARAMETER MEASUREMENT INFORMATION

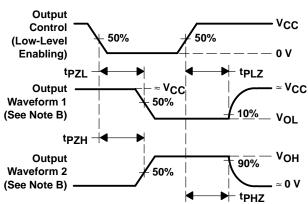


PARAI	METER	RL	CL	S1	S2
t <sub>PZH</sub> 50 pF 1 kΩ or		Open	Closed		
ten	tPZL	1 K22	150 pF	Closed	Open
4	tPHZ	<b>1 k</b> Ω	50 pF	Open	Closed
<sup>t</sup> dis	tPLZ	1 K22	30 pr	Closed	Open
t <sub>pd</sub> or	t <sub>t</sub>	-	50 pF or 150 pF	Open	Open



VOLTAGE WAVEFORMS
PROPAGATION DELAY AND OUTPUT TRANSITION TIMES





VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES FOR 3-STATE OUTPUTS

- NOTES: A. C<sub>L</sub> includes probe and test-fixture capacitance.
  - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
  - C. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz,  $Z_O = 50 \Omega$ ,  $t_r = 6$  ns.
  - D. The outputs are measured one at a time with one input transition per measurement.
  - E. tpLz and tpHz are the same as tdis.
  - F. tpzL and tpzH are the same as ten.
  - G. tplH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



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